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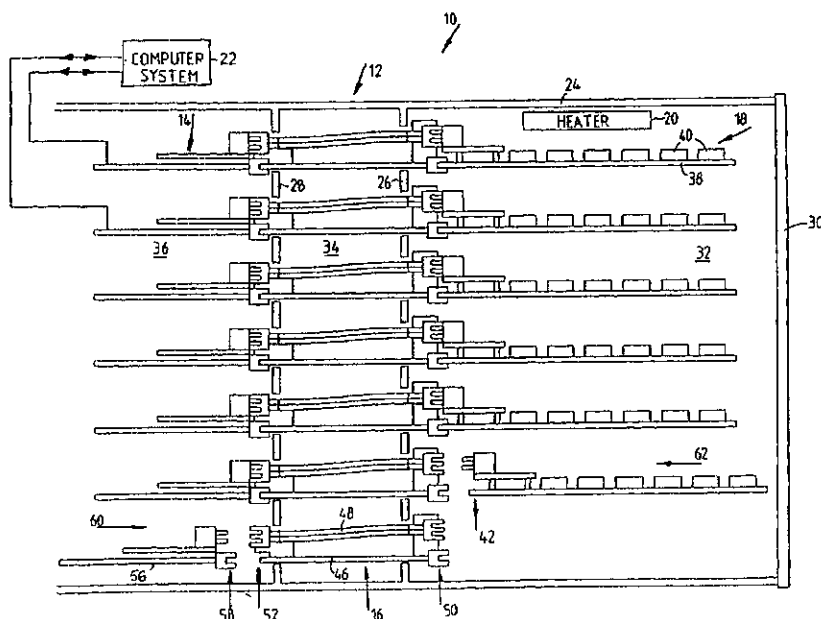
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(54) Title: A SYSTEM FOR BURN-IN TESTING OF ELECTRONIC DEVICES



(57) Abstract: A system (10) is provided which allows for burn-in testing of electronic devices wherein power current is provided individually to each one of the electronic devices. The system also includes various connectors, cables, and other configurations that allow for power currents having large magnitudes to be provided to the electronic devices. It comprises a housing (12), a plurality of burn-in testing driver board assemblies (14), a plurality of feed through assemblies (16), a plurality of burn-in board assemblies (18), a heater (20), and a computer system (22).



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